


<b>Search Notes</b>  	<b>Application/Control No.</b>  10779319	<b>Applicant(s)/Patent Under Reexamination</b>  DRESSER ET AL.
	<b>Examiner</b>  Chawan, Sheela C	<b>Art Unit</b>  2624

### SEARCHED

Class	Subclass	Date	Examiner
382	154, 173, 190, 255, 254, 260, 264, 263, 274, 275	6/23/07	SCC
250	201.8, 204, 208.1, 201.2, 204, 223R, 227.24, 566, 226,	"	"
396	114, 101, 111, 128, 104, 107	"	"
359	350, 839, 306, 579	"	"
358	474, 119	:"	"
348	350, E5.045, E13.007, E13.009, E13.014, E13.009, E13.014, E13.016, E13.024, E13.025, E5.045, 350	"	"
382	154, 255,	7/4/08	SCC
359	306, 579	7/4/08	SCC
ABOVE SEARCH UP-DATE		7/4/08	SCC

### SEARCH NOTES

Search Notes	Date	Examiner
SEARCH EAST AND OTHER DATABASES , SEE THE SEARCH HISTORY.	6/23/07	SCC
INVENTOR NAME SEARCH.	"	"
SEARCH EAST AND OTHER DATA BASE , SEE THE ATTACHED SEARCH HISTORY	7/4/08	SCC
382/154, 255, 264.CCLS. US-PATENT ONLY , SEE TEXT SEARCH.	7/4/08	SCC
INTERFERENCE SEARCH , SEE SEARCH HISTORY PRINT OUT.	7/4/08	SCC
SEARCH IEEE OR INSPECT DATA BASE.	7/4/08	SCC
ABOVE SEARCH UP-DATE.	7/4/08	SCC
359/306, 579.CCLS. US-PATENT ONLY SEE TEXT SEARCH.	7/4/08	SCC

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
382	154, 255,	7/4/08	SCC
359	306, 579	7/4/08	SCC